

B C Regan

List of Publications by Year in descending order

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71
papers

1,382
citations

516215

16
h-index

329751

37
g-index

73
all docs

73
docs citations

73
times ranked

2507
citing authors

#	ARTICLE	IF	CITATIONS
1	Carbon nanotubes as nanoscale mass conveyors. <i>Nature</i> , 2004, 428, 924-927.	13.7	291
2	Nanoscale temperature mapping in operating microelectronic devices. <i>Science</i> , 2015, 347, 629-632.	6.0	253
3	Nanofilament Formation and Regeneration During Cu/Al ₂ O ₃ Resistive Memory Switching. <i>Nano Letters</i> , 2015, 15, 3983-3987.	4.5	123
4	Charged Nanoparticle Dynamics in Water Induced by Scanning Transmission Electron Microscopy. <i>Langmuir</i> , 2012, 28, 3695-3698.	1.6	107
5	Spin and the Honeycomb Lattice: Lessons from Graphene. <i>Physical Review Letters</i> , 2011, 106, 116803.	2.9	97
6	Chemical Vapor Deposition of Graphene on Copper from Methane, Ethane and Propane: Evidence for Bilayer Selectivity. <i>Small</i> , 2012, 8, 1415-1422.	5.2	93
7	In situ coherent diffractive imaging. <i>Nature Communications</i> , 2018, 9, 1826.	5.8	52
8	Imaging the life story of nanotube devices. <i>Applied Physics Letters</i> , 2005, 87, 083103.	1.5	50
9	Probing Planck's Law with Incandescent Light Emission from a Single Carbon Nanotube. <i>Physical Review Letters</i> , 2009, 102, 187402.	2.9	39
10	Dark-field transmission electron microscopy and the Debye-Waller factor of graphene. <i>Physical Review B</i> , 2013, 87, 045417.	1.1	35
11	STEM Imaging with Beam-Induced Hole and Secondary Electron Currents. <i>Physical Review Applied</i> , 2018, 10, .	1.5	29
12	Polarized light emission from individual incandescent carbon nanotubes. <i>Physical Review B</i> , 2011, 83, .	1.1	24
13	Tree-level electron-photon interactions in graphene. <i>Physical Review B</i> , 2010, 81, .	1.1	23
14	Electron beam-induced current imaging with two-angstrom resolution. <i>Ultramicroscopy</i> , 2019, 207, 112852.	0.8	23
15	Intercalation events visualized in single microcrystals of graphite. <i>Nature Communications</i> , 2017, 8, 1969.	5.8	21
16	Imaging interfacial electrical transport in graphene-MoS ₂ heterostructures with electron-beam-induced-currents. <i>Applied Physics Letters</i> , 2015, 107, 223104.	1.5	18
17	Irreversibility at macromolecular scales in the flake graphite of the lithium-ion battery anode. <i>Journal of Power Sources</i> , 2019, 436, 226841.	4.0	16
18	Electron-Transparent Thermoelectric Coolers Demonstrated with Nanoparticle and Condensation Thermometry. <i>ACS Nano</i> , 2020, 14, 11510-11517.	7.3	11

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19	Imaging Dielectric Breakdown in Valence Change Memory. <i>Advanced Functional Materials</i> , 2022, 32, 2102313.	7.8	10
20	Single-color pyrometry of individual incandescent multiwalled carbon nanotubes. <i>Physical Review B</i> , 2011, 84, .	1.1	9
21	In Situ Transmission Electron Microscopy of the Electrochemical Intercalation of Graphite in Concentrated Sulfuric Acid. <i>Microscopy and Microanalysis</i> , 2014, 20, 1528-1529.	0.2	9
22	Measuring nanoscale thermal gradients in suspended MoS ₂ with STEM-EELS. <i>Applied Physics Letters</i> , 2019, 115, .	1.5	9
23	Visualizing the Electron Wind Force in the Elastic Regime. <i>Nano Letters</i> , 2021, 21, 10172-10177.	4.5	8
24	In Situ STEM of Ag and Cu Conducting Bridge Formation through Al ₂ O ₃ in Nanoscale Resistive Memory Devices. <i>Microscopy and Microanalysis</i> , 2014, 20, 1550-1551.	0.2	3
25	Secondary Electron Contrast in STEM Electron Beam-Induced Current (EBIC): a Path Towards Mapping Electronic Structure. <i>Microscopy and Microanalysis</i> , 2018, 24, 1846-1847.	0.2	3
26	STEM Video of Electronically-Driven Metal-Insulator Transitions in Nanoscale NbO ₂ Devices. <i>Microscopy and Microanalysis</i> , 2016, 22, 1254-1255.	0.2	2
27	In Situ Optical Microscopy of the Electrochemical Intercalation of Lithium into Single Crystal Graphite. <i>Microscopy and Microanalysis</i> , 2017, 23, 1982-1983.	0.2	2
28	Adjusting the STEM Sample Holder Potential for Improved EBIC Contrast. <i>Microscopy and Microanalysis</i> , 2019, 25, 2354-2355.	0.2	2
29	STEM of a Single Crystal Lithium Ion Battery Anode during Electrochemical Cycling. <i>Microscopy and Microanalysis</i> , 2019, 25, 2060-2061.	0.2	2
30	Differential electron yield imaging with STXM. <i>Ultramicroscopy</i> , 2021, 222, 113198.	0.8	2
31	STEM EBIC to Study 2D Materials. <i>Microscopy and Microanalysis</i> , 2014, 20, 172-173.	0.2	1
32	In Situ Scanning Transmission Electron Microscopy (STEM) of Individual Electrochemical Intercalation Events in Graphite. <i>Microscopy and Microanalysis</i> , 2015, 21, 1193-1194.	0.2	1
33	Aluminum Nanoparticles as Fiducials for Nanoscale Temperature Measurements. <i>Microscopy and Microanalysis</i> , 2016, 22, 830-831.	0.2	1
34	Aloof Beam Plasmons in Silver Nanoparticles. <i>Microscopy and Microanalysis</i> , 2016, 22, 1642-1643.	0.2	1
35	Temperature Dependence of the Silicon Nitride Volume Plasmon. <i>Microscopy and Microanalysis</i> , 2016, 22, 1574-1575.	0.2	1
36	In Situ Video Observations of the Lithiation of Single Microcrystal Graphite. <i>Microscopy and Microanalysis</i> , 2016, 22, 1384-1385.	0.2	1

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37	STEM EBIC Mapping of the Metal-Insulator Transition in Thin-film NbO ₂ . Microscopy and Microanalysis, 2017, 23, 1428-1429.	0.2	1
38	Scanning TEM EBIC Imaging of Resistive Memory Switching Processes. Microscopy and Microanalysis, 2018, 24, 1806-1807.	0.2	1
39	Secondary-Electron Electron-Beam-Induced Current Measurements at Lattice Resolution. Microscopy and Microanalysis, 2019, 25, 1656-1657.	0.2	1
40	Mean Angular Deviation Minimization To Determine Lattice Parameters in Transmission Kikuchi Diffraction. Microscopy and Microanalysis, 2021, 27, 1608-1609.	0.2	1
41	Mapping Charge Recombination and the Effect of Point-Defect Insertion in GaAs Nanowire Heterojunctions. Physical Review Applied, 2021, 16, .	1.5	1
42	STEM EBIC Thermometry Calibration with PEET on Al Nanoparticles. Microscopy and Microanalysis, 2020, 26, 3124-3125.	0.2	1
43	Three-Dimensional Imaging of Dislocations and Defects in Materials at Atomic Resolution Using Electron Tomography. Microscopy and Microanalysis, 2014, 20, 1062-1063.	0.2	0
44	Nanobubbles on Electron Transparent Electrodes. Microscopy and Microanalysis, 2014, 20, 1610-1611.	0.2	0
45	Impedance matching of inverted conductors: Two-dimensional beam splitters with divergent gain. Physical Review A, 2015, 92, .	1.0	0
46	Time-Resolved Imaging of Electrochemical Switching in Nanoscale Resistive Memory Elements. Microscopy and Microanalysis, 2015, 21, 1911-1912.	0.2	0
47	Applications of Plasmon Energy Expansion Thermometry. Microscopy and Microanalysis, 2015, 21, 663-664.	0.2	0
48	Introduction to Plasmon Energy Expansion Thermometry. Microscopy and Microanalysis, 2015, 21, 1907-1908.	0.2	0
49	Nanoscale Mapping of Interfacial Electrical Transport in Graphene-MoS ₂ Heterostructures with STEM-EBIC. Microscopy and Microanalysis, 2016, 22, 1552-1553.	0.2	0
50	Temperature Dependence of the Volume Plasmon in Silicon Nanoparticles. Microscopy and Microanalysis, 2016, 22, 296-297.	0.2	0
51	Asymmetric Temperature Profiles in Joule-Heated in Aluminum Nanowires. Microscopy and Microanalysis, 2016, 22, 772-773.	0.2	0
52	Plasmon Energy Mapping in Aluminum and Indium with Sub-Nanometer Resolution. Microscopy and Microanalysis, 2017, 23, 378-379.	0.2	0
53	Temperature-dependent signals in STEM Electron Beam-Induced Current (EBIC) Imaging. Microscopy and Microanalysis, 2017, 23, 1506-1507.	0.2	0
54	Detailed In Situ Observations of Electromigration in Aluminum Wires. Microscopy and Microanalysis, 2017, 23, 1450-1451.	0.2	0

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55	In Situ Observation of Cooling in a Bismuth Telluride and Bismuth-Antimony Telluride Nanoscale Heterojunction. <i>Microscopy and Microanalysis</i> , 2017, 23, 1996-1997.	0.2	0
56	Scanning TEM Electron Beam Induced Current Imaging in Water. <i>Microscopy and Microanalysis</i> , 2018, 24, 252-253.	0.2	0
57	Electromigration of Copper in Lithographically-Defined Aluminum Nanowires. <i>Microscopy and Microanalysis</i> , 2018, 24, 2190-2191.	0.2	0
58	Total Electron Yield Mapping of Electronic Device Features via Measurement of X-Ray Beam-Induced Currents. <i>Microscopy and Microanalysis</i> , 2019, 25, 256-257.	0.2	0
59	Mapping Electronic State Changes with STEM EBIC. <i>Microscopy and Microanalysis</i> , 2019, 25, 1396-1397.	0.2	0
60	Inducing Electrically-Active Defects in a Gallium Arsenide Nanowire with an Electron Beam. <i>Microscopy and Microanalysis</i> , 2019, 25, 1618-1619.	0.2	0
61	Mapping Ferroelectricity in Hafnia Thin Films with STEM EBIC. <i>Microscopy and Microanalysis</i> , 2019, 25, 1846-1847.	0.2	0
62	Correlation of Joule Heating and Electromigration-induced Mass Transport within Nanoscale Co Interconnects by In Situ STEM. <i>Microscopy and Microanalysis</i> , 2020, 26, 152-154.	0.2	0
63	Electrical Isolation Preserved by Plasma Focused Ion Beam TEM Sample Preparation and Verified with STEM SEEBIC Imaging. <i>Microscopy and Microanalysis</i> , 2020, 26, 194-195.	0.2	0
64	Nanoparticle Temperature Measurements for MEMS Heater Calibration. <i>Microscopy and Microanalysis</i> , 2020, 26, 1226-1227.	0.2	0
65	In Situ STEM Observations of Elemental Segregation in Phase Change Material GST Under Electrical and Thermal Stress. <i>Microscopy and Microanalysis</i> , 2021, 27, 168-169.	0.2	0
66	Modern STEM EBIC: Emerging Modes and Methods. <i>Microscopy and Microanalysis</i> , 2021, 27, 2350-2352.	0.2	0
67	Technique and Computational Improvements in 4D STEM and Cross-Correlation Analysis. <i>Microscopy and Microanalysis</i> , 2021, 27, 1540-1541.	0.2	0
68	Imaging Soft and Hard Dielectric Breakdown in Resistive Switching. <i>Microscopy and Microanalysis</i> , 2021, 27, 2354-2355.	0.2	0
69	Determining Lattice Parameters by Curve-Fitting Transmission Kikuchi Diffraction Patterns. <i>Microscopy and Microanalysis</i> , 2021, 27, 2020-2021.	0.2	0
70	In Situ Visualization of the Electron Wind Force in the Elastic Regime. <i>Microscopy and Microanalysis</i> , 2021, 27, 106-107.	0.2	0
71	Chemical Shift Detection with Energy Dispersive Spectroscopy (EDS). <i>Microscopy and Microanalysis</i> , 2021, 27, 2068-2069.	0.2	0